



RESPONSE UNDER 37 C.F.R. §1.116
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EXPEDITED PROCEDURE
EXAMINING GROUP 2123

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DOCKET NO. 122.1329/CJG

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Hisanori FUJISAWA

Serial No.: 09/045,041

Group Art Unit: 2123

Confirmation No.: 9340

Filed: March 20, 1998

Examiner: H. Jones

For: METHOD AND APPARATUS FOR CARRYING OUT CIRCUIT SIMULATION

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RESPONSE AND REQUEST FOR RECONSIDERATION
UNDER 37 C.F.R. 1.116
- EXPEDITED PROCEDURE -

Assistant Commissioner for Patents
Washington, D.C. 20231

Sir:

This is in response to the final Office Action mailed November 27, 2002, having a shortened period for response set to expire on February 27, 2003. A Notice of Appeal is filed concurrently herewith. The following amendments and remarks are respectfully submitted.

IN THE CLAIMS:

Please **AMEND** claims 18, 30, and 42 as follows:

18. (ONCE AMENDED) The method of claim 17, wherein said assessing the intensity of influence of an external terminal is determined as the frequency of shifting from the source or drain of a MOS semiconductor device to the gate thereof while tracing a path linking the external terminal and one or more terminals of each of the plurality of partial circuits.